

# IGBT - Field Stop, Trench

650 V, 40 A

## FGH40T65SPD

### Description

Using novel field stop IGBT technology, ON Semiconductor's new series of field stop 3<sup>rd</sup> generation IGBTs offer the optimum performance for solar inverter, UPS, welder, telecom, ESS and PFC applications where low conduction and switching losses are essential.

### Features

- Maximum Junction Temperature:  $T_J = 175^{\circ}\text{C}$
- Positive Temperature Co-efficient for Easy Parallel Operating
- High Current Capability
- Low Saturation Voltage:  $V_{CE(sat)} = 1.85\text{ V (Typ.) @ } I_C = 40\text{ A}$
- High Input Impedance
- Fast Switching
- Tighten Parameter Distribution
- Short Circuit Ruggedness  $> 5\text{ }\mu\text{s @ } 25^{\circ}\text{C}$
- This Device is Pb-Free and is RoHS Compliant

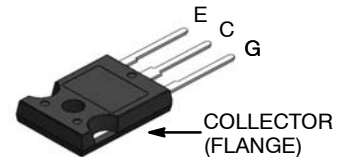
### Applications

- Solar Inverter, UPS, Welder, PFC, Telecom, ESS



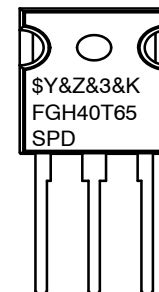
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TO-247-3LD  
CASE 340CH

### MARKING DIAGRAM



\$Y	= ON Semiconductor Logo
&Z	= Assembly Plant Code
&3	= Numeric Date Code
&K	= Lot Code
FGH40T65SPD	= Specific Device Code

### ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 2 of this data sheet.

# FGH40T65SPD

## ABSOLUTE MAXIMUM RATINGS

Description		Symbol	FGH40T65SPD–F155	Unit
Collector to Emitter Voltage		V <sub>CES</sub>	650	V
Gate to Emitter Voltage		V <sub>GES</sub>	±20	V
Transient Gate to Emitter Voltage			±30	V
Collector Current	T <sub>C</sub> = 25°C	I <sub>C</sub>	80	A
Collector Current	T <sub>C</sub> = 100°C		40	A
Pulsed Collector Current (Note 2)		I <sub>CM</sub>	120	A
Diode Forward Current	T <sub>C</sub> = 25°C	I <sub>F</sub>	40	A
Diode Forward Current	T <sub>C</sub> = 100°C		20	A
Pulsed Diode Maximum Forward Current		I <sub>FM</sub>	120	A
Maximum Power Dissipation	T <sub>C</sub> = 25°C	P <sub>D</sub>	267	W
Maximum Power Dissipation	T <sub>C</sub> = 100°C		134	W
Short Circuit Withstand Time	T <sub>C</sub> = 25°C	SCWT	5	μs
Operating Junction Temperature		T <sub>J</sub>	–55 to +175	°C
Storage Temperature Range		T <sub>stg</sub>	–55 to +175	°C
Maximum Lead Temp. for Soldering Purposes, 1/8" from Case for 5 Seconds		T <sub>L</sub>	300	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. Repetitive Rating: Pulse width limited by max. junction temperature.

## THERMAL CHARACTERISTICS

Parameter	Symbol	Typ	Max	Unit
Thermal Resistance, Junction to Case (IGBT)	$R_{\theta JC}$	–	0.56	$^\circ\text{C/W}$
Thermal Resistance, Junction to Case (Diode)	$R_{\theta JC}$	–	1.71	$^\circ\text{C/W}$
Thermal Resistance, Junction to Ambient	$R_{\theta JA}$	–	40	$^\circ\text{C/W}$

## PACKAGE MARKING AND ORDERING INFORMATION

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FGH40T65SPD	FGH40T65SPD-F155	TO-247-3LD	–	–	30

## ELECTRICAL CHARACTERISTICS OF THE IGBT ( $T_C = 25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
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### OFF CHARACTERISTICS

Collector to Emitter Breakdown Voltage	$BV_{CES}$	$V_{GE} = 0\text{ V}, I_C = 1\text{ mA}$	650	–	–	V
Temperature Coefficient of Breakdown Voltage	$\Delta BV_{CES}/\Delta T_J$	$V_{GE} = 0\text{ V}, I_C = 1\text{ mA}$		0.6		$\text{V}/^\circ\text{C}$
Collector Cut-Off Current	$I_{CES}$	$V_{CE} = V_{CES}, V_{GE} = 0\text{ V}$	–	–	250	$\mu\text{A}$
G–E Leakage Current	$I_{GES}$	$V_{GE} = V_{GES}, V_{CE} = 0\text{ V}$	–	–	$\pm 400$	nA

### ON CHARACTERISTICS

G–E Threshold Voltage	$V_{GE(th)}$	$I_C = 40\text{ mA}, V_{CE} = V_{GE}$	4	5.5	7.5	V
Collector to Emitter Saturation Voltage	$V_{CE(sat)}$	$I_C = 40\text{ A}, V_{GE} = 15\text{ V}$	–	1.85	2.4	V
		$I_C = 40\text{ A}, V_{GE} = 15\text{ V}, T_C = 175^\circ\text{C}$	–	2.51	–	V

# FGH40T65SPD

## ELECTRICAL CHARACTERISTICS OF THE IGBT ( $T_C = 25^\circ\text{C}$ unless otherwise noted) (continued)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
DYNAMIC CHARACTERISTICS						
Input Capacitance	C <sub>ies</sub>	V <sub>CE</sub> = 30 V, V <sub>GE</sub> = 0 V, f = 1 MHz	–	1370	–	pF
Output Capacitance	C <sub>oes</sub>		–	94	–	pF
Reverse Transfer Capacitance	C <sub>res</sub>		–	16	–	pF
SWITCHING CHARACTERISTICS						
Turn-On Delay Time	T <sub>d(on)</sub>	V <sub>CC</sub> = 400 V, I <sub>C</sub> = 40 A, R <sub>G</sub> = 6 Ω, V <sub>GE</sub> = 15 V, Inductive Load, T <sub>C</sub> = 25°C	–	16	–	ns
Rise Time	T <sub>r</sub>		–	42	–	ns
Turn-Off Delay Time	T <sub>d(off)</sub>		–	37	–	ns
Fall Time	T <sub>f</sub>		–	11	–	ns
Turn-On Switching Loss	E <sub>on</sub>		–	1.16	–	mJ
Turn-Off Switching Loss	E <sub>off</sub>		–	0.28	–	mJ
Total Switching Loss	E <sub>ts</sub>		–	1.44	–	mJ
Turn-On Delay Time	T <sub>d(on)</sub>	V <sub>CC</sub> = 400 V, I <sub>C</sub> = 40 A, R <sub>G</sub> = 6 Ω, V <sub>GE</sub> = 15 V, Inductive Load, T <sub>C</sub> = 175°C	–	14	–	ns
Rise Time	T <sub>r</sub>		–	49	–	ns
Turn-Off Delay Time	T <sub>d(off)</sub>		–	38	–	ns
Fall Time	T <sub>f</sub>		–	18	–	ns
Turn-On Switching Loss	E <sub>on</sub>		–	1.54	–	mJ
Turn-Off Switching Loss	E <sub>off</sub>		–	0.52	–	mJ
Total Switching Loss	E <sub>ts</sub>		–	2.06	–	mJ
Short Circuit Withstand Time	T <sub>SC</sub>	V <sub>CC</sub> = 400 V, V <sub>GE</sub> = 15 V, R <sub>G</sub> = 10 Ω	5	–	–	μs
Total Gate Charge	Q <sub>g</sub>	V <sub>CC</sub> = 400 V, I <sub>C</sub> = 40 A, V <sub>GE</sub> = 15 V	–	35	–	nC
Gate to Emitter Charge	Q <sub>ge</sub>		–	11	–	nC
Gate to Collector Charge	Q <sub>gc</sub>		–	12	–	nC

## ELECTRICAL CHARACTERISTICS OF THE DIODE ( $T_J = 25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Test Conditions		Min	Typ	Max	Unit
Diode Forward Voltage	V <sub>FM</sub>	I <sub>F</sub> = 20 A	T <sub>C</sub> = 25°C	–	2.2	2.7	V
			T <sub>C</sub> = 175°C	–	1.9	–	
Reverse Recovery Energy	E <sub>rec</sub>	I <sub>F</sub> = 20 A, dI <sub>F</sub> /dt = 200 A/μs	T <sub>C</sub> = 175°C	–	76	–	μJ
Diode Reverse Recovery Time	T <sub>rr</sub>		T <sub>C</sub> = 25°C	–	34	–	ns
			T <sub>C</sub> = 175°C	–	196	–	
Diode Reverse Recovery Charge	Q <sub>rr</sub>		T <sub>C</sub> = 25°C	–	52	–	nC
			T <sub>C</sub> = 175°C	–	638	–	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

TYPICAL PERFORMANCE CHARACTERISTICS

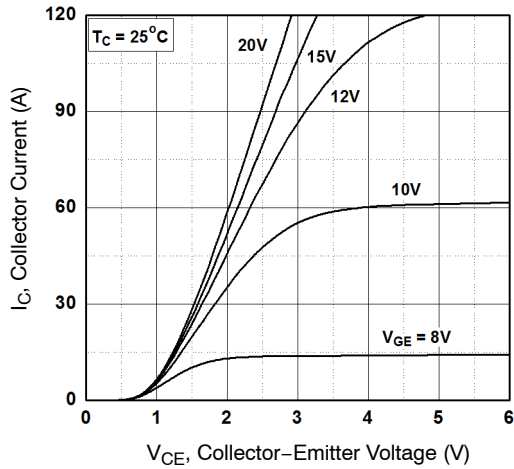


Figure 1. Typical Output Characteristics

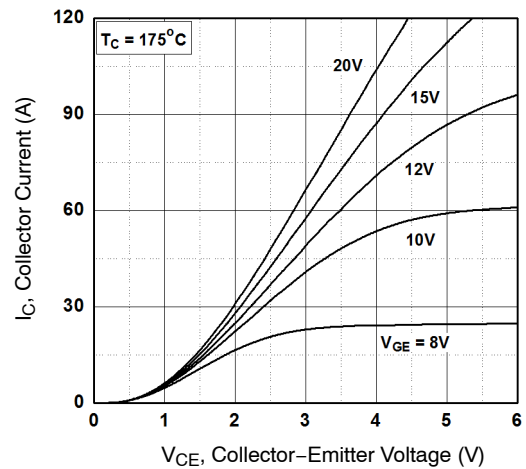


Figure 2. Typical Output Characteristics

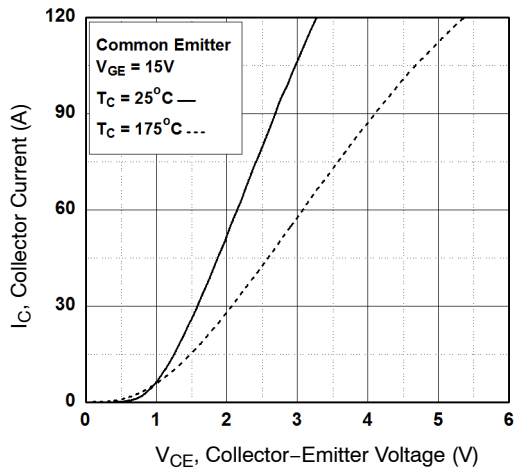


Figure 3. Typical Saturation Voltage Characteristics

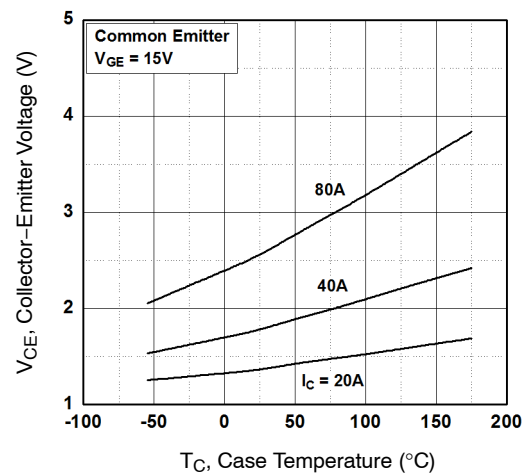


Figure 4. Saturation Voltage vs. Case Temperature at Variant Current Level

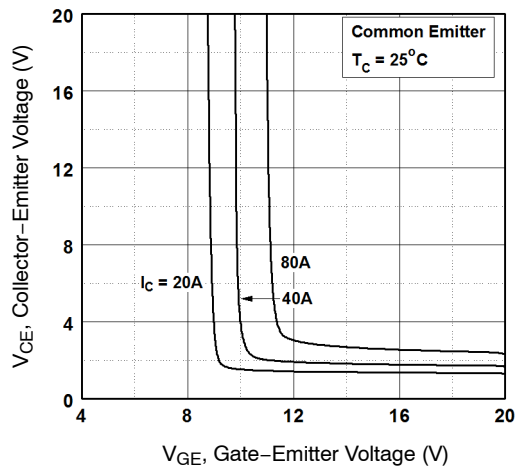


Figure 5. Saturation Voltage vs  $V_{GE}$

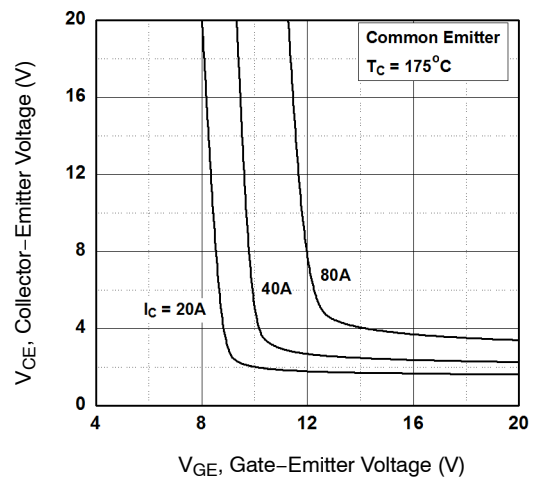


Figure 6. Saturation Voltage vs  $V_{GE}$

TYPICAL PERFORMANCE CHARACTERISTICS (continued)

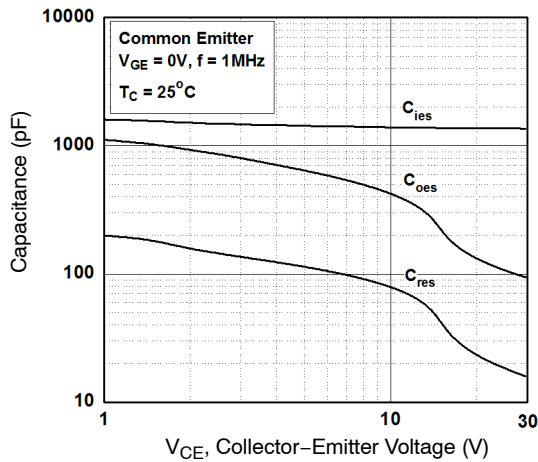


Figure 7. Capacitance Characteristics

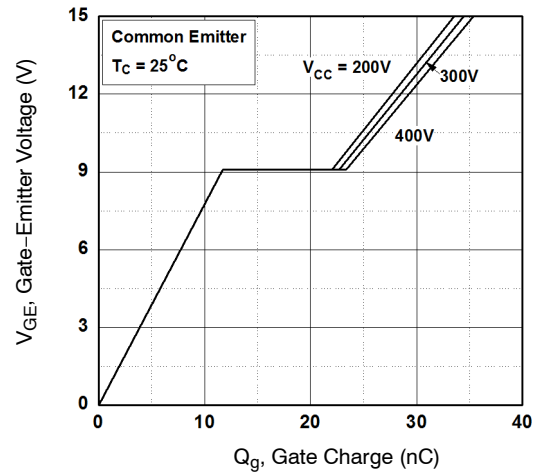


Figure 8. Gate Charge Characteristics

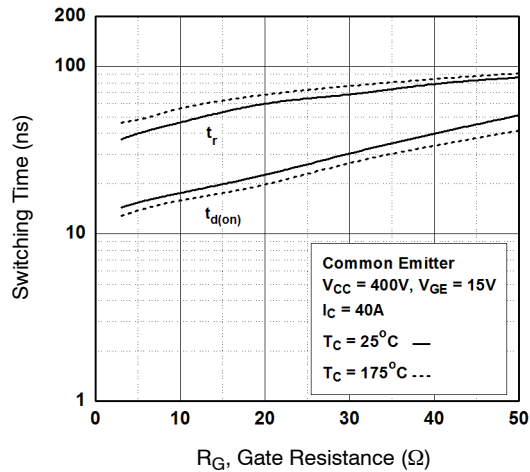


Figure 9. Turn-On Characteristics vs. Gate Resistance

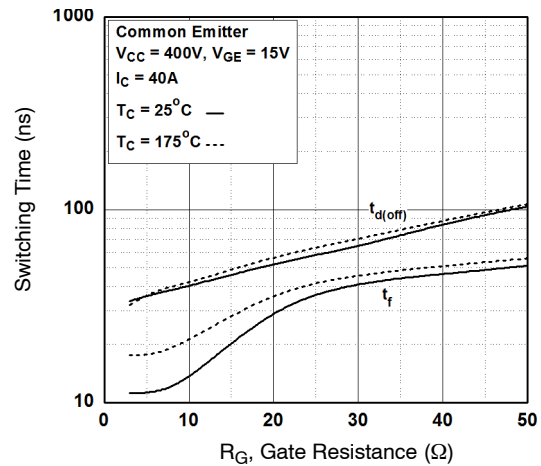


Figure 10. Turn-Off Characteristics vs. Gate Resistance

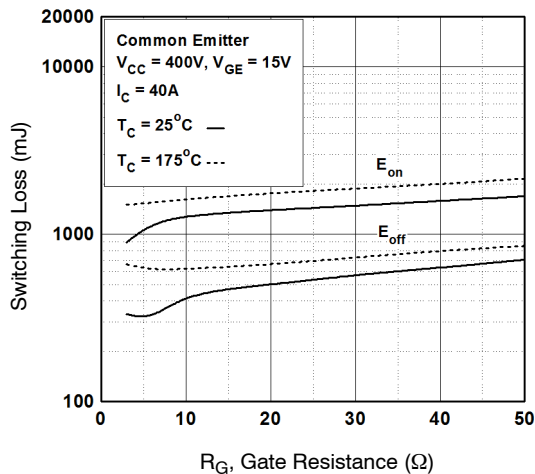


Figure 11. Switching Loss vs. Gate Resistance

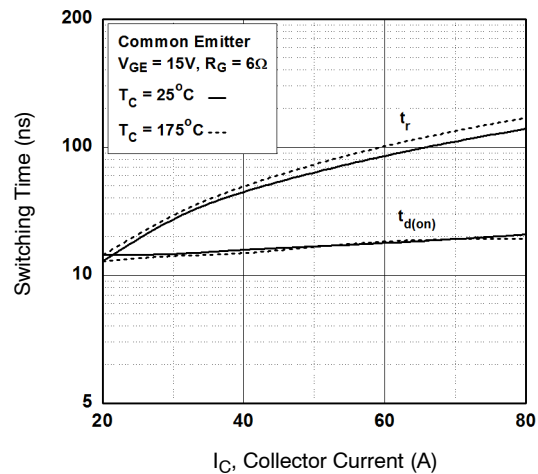


Figure 12. Turn-On Characteristics vs. Collector Current

TYPICAL PERFORMANCE CHARACTERISTICS (continued)

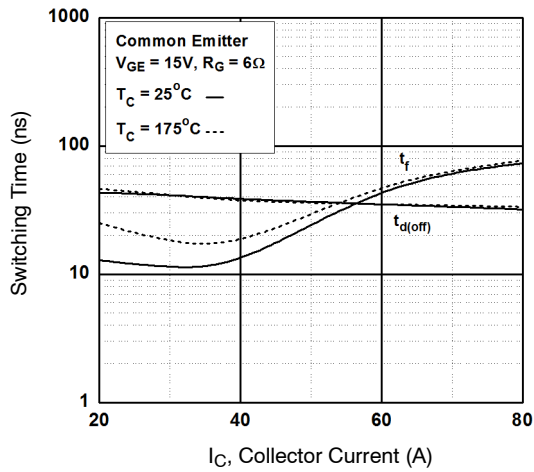


Figure 13. Turn-Off Characteristics vs. Collector Current

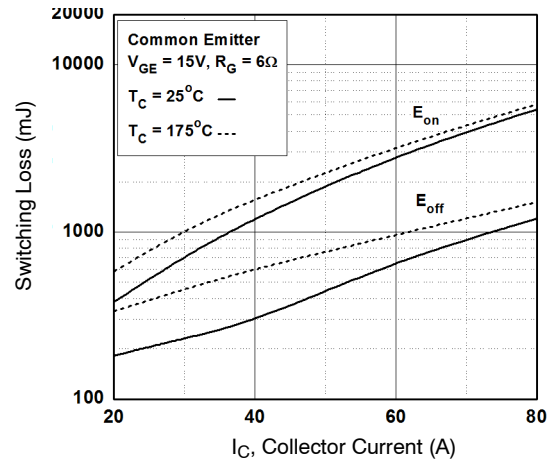


Figure 14. Switching Loss vs. Collector Current

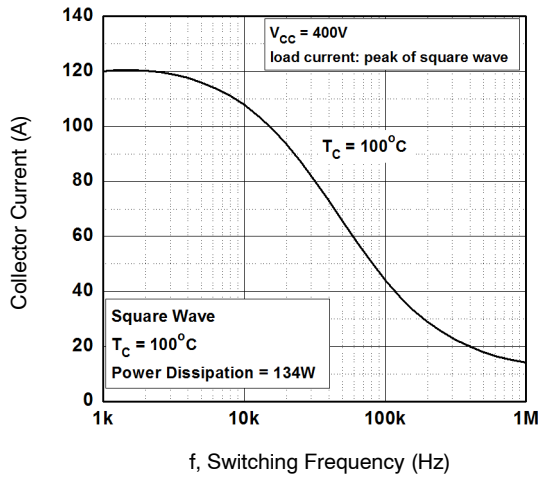


Figure 15. Load Current vs. Frequency

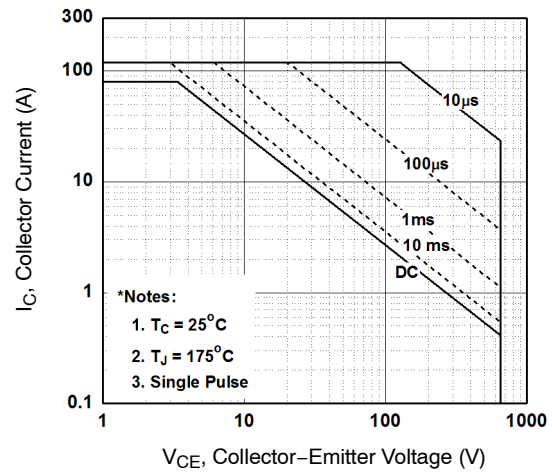


Figure 16. SOA Characteristics

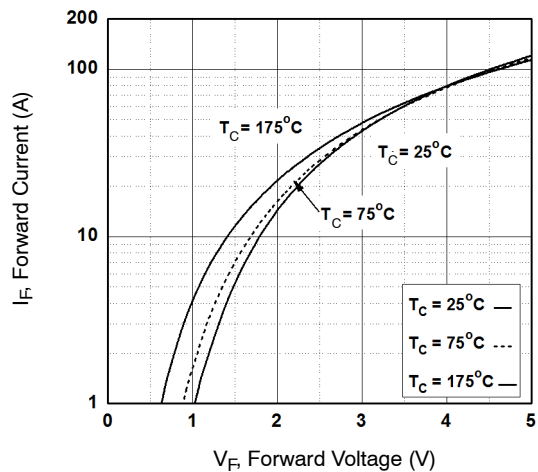


Figure 17. Forward Characteristics

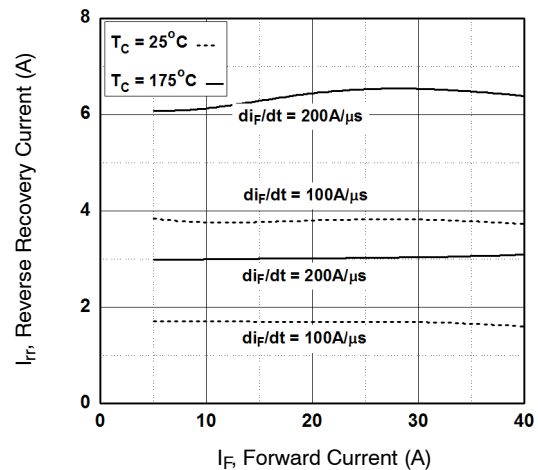


Figure 18. Reverse Recovery Current

TYPICAL PERFORMANCE CHARACTERISTICS (continued)

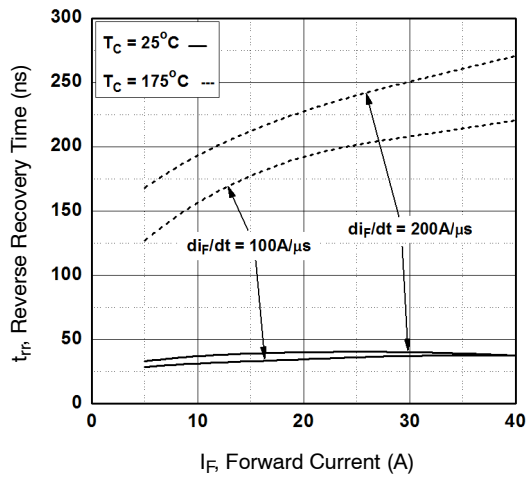


Figure 19. Reverse Recovery Time

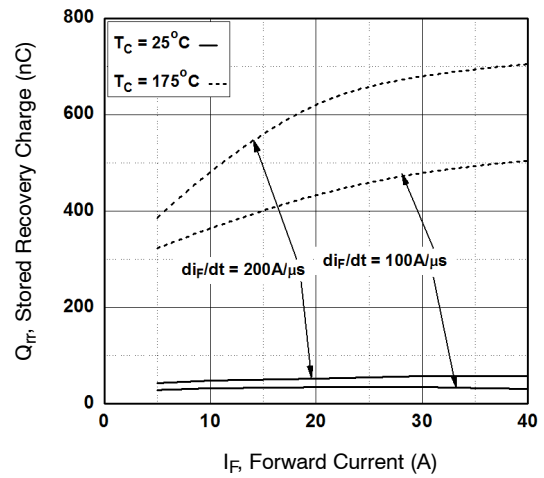


Figure 20. Stored Charge

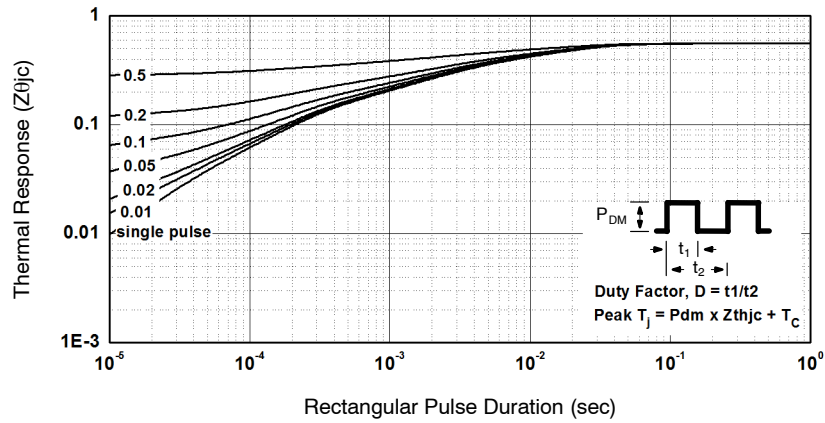


Figure 21. Transient Thermal Impedance of IGBT

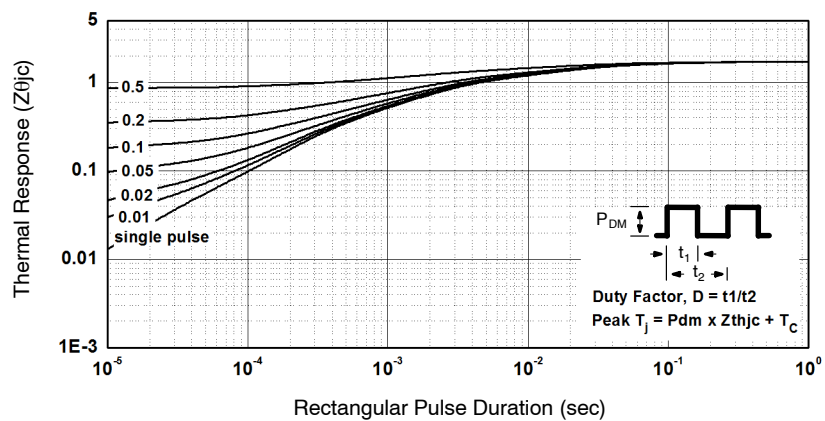
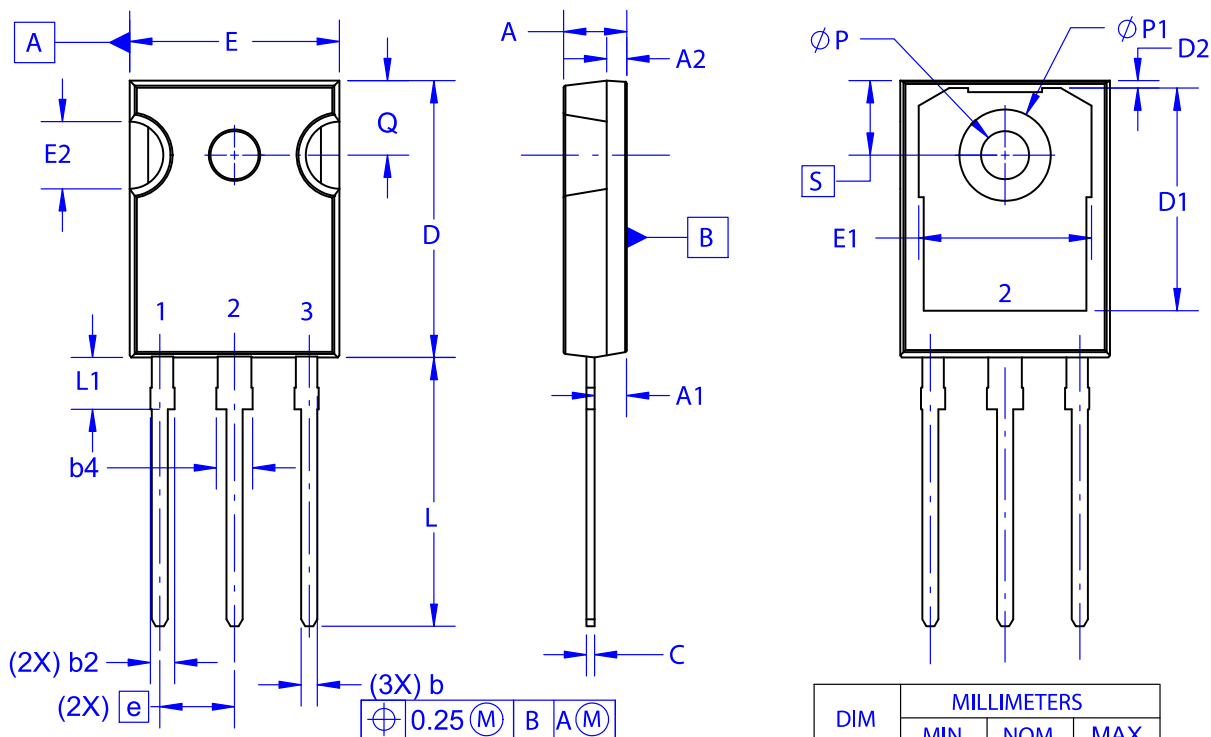


Figure 22. Transient Thermal Impedance of Diode

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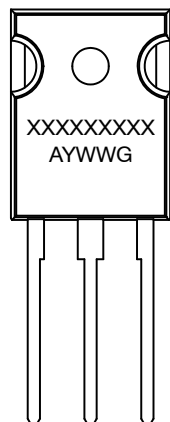
DATE 09 OCT 2019



NOTES: UNLESS OTHERWISE SPECIFIED.

- A. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS.
- B. ALL DIMENSIONS ARE IN MILLIMETERS.
- C. DRAWING CONFORMS TO ASME Y14.5 - 2009.
- D. DIMENSION A1 TO BE MEASURED IN THE REGION DEFINED BY L1.
- E. LEAD FINISH IS UNCONTROLLED IN THE REGION DEFINED BY L1.

#### GENERIC MARKING DIAGRAM\*



XXXX = Specific Device Code  
A = Assembly Location  
Y = Year  
WW = Work Week  
G = Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.

DIM	MILLIMETERS		
	MIN	NOM	MAX
A	4.58	4.70	4.82
A1	2.29	2.475	2.66
A2	1.40	1.50	1.60
D	20.32	20.57	20.82
E	15.37	15.62	15.87
E2	4.96	5.08	5.20
e	~	5.56	~
L	19.75	20.00	20.25
L1	3.69	3.81	3.93
ØP	3.51	3.58	3.65
Q	5.34	5.46	5.58
S	5.34	5.46	5.58
b	1.17	1.26	1.35
b2	1.53	1.65	1.77
b4	2.42	2.54	2.66
c	0.51	0.61	0.71
D1	13.08	~	~
D2	0.51	0.93	1.35
E1	12.81	~	~
ØP1	6.61	6.73	6.85

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